

### IRFB20N50K-VB Datasheet

## N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650				
R <sub>DS(on)</sub> (Ω) at 25 °C	V <sub>GS</sub> = 10 V	0.19			
Q <sub>g</sub> max. (nC)	106				
Q <sub>gs</sub> (nC)	14				
Q <sub>gd</sub> (nC)	33				
Configuration	Single				

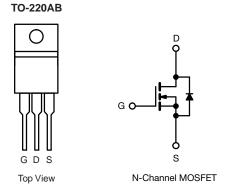
# **FEATURES**

- Reduced t<sub>rr</sub>, Q<sub>rr</sub>, and I<sub>RRM</sub>
- ullet Low figure-of-merit (FOM)  $R_{on} \times Q_{g}$
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q<sub>rr</sub>
- Ultra low gate charge (Qa)
- Avalanche energy rated (UIS)



#### **APPLICATIONS**

- Telecommunications
  - Server and telecom power supplies
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Consumer and computing
  - ATX power supplies
- Industrial
  - Welding
  - Battery chargers
- Renewable energy
  - Solar (PV inverters)
- Switch mode power supplies (SMPS)



<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	650	V	
Gate-Source Voltage			$V_{GS}$	± 30		
Continuous Dusin Courset (T. 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	20		
Continuous Drain Current (T <sub>J</sub> = 150 °C)		T <sub>C</sub> = 100 °C		13	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	60		
Linear Derating Factor				1.7	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	367	mJ	
Maximum Power Dissipation			$P_{D}$	208	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		d\//d+	37	\//no	
Reverse Diode dV/dt <sup>d</sup>			dV/dt	31	- V/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	e) c for 10 s			300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=5.1$  A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ , dI/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.5	G/ VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2	-	4	V
0.1.0		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 30 \text{ V}$		-	± 1	μΑ
Zava Cata Valtaga Dvain Cuwant		V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	-	1	μА
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			-	-	500	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A	-	0.19	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 11 A	-	7.0	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,	-	2322	-	
Output Capacitance	C <sub>oss</sub>	1	$V_{DS} = 100 \text{ V},$	-	105	-	1
Reverse Transfer Capacitance	C <sub>rss</sub>	7	f = 1 MHz		4	-	pF
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V$		-	84	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	293	-	
Total Gate Charge	$Q_g$		V <sub>GS</sub> = 10 V I <sub>D</sub> = 11 A, V <sub>DS</sub> = 520 V		71	106	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V			14	-	
Gate-Drain Charge	Q <sub>gd</sub>	1			33	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 11 A,		-	22	44	ns
Rise Time	t <sub>r</sub>			-	34	68	
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> =	$V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		68	102	
Fall Time	t <sub>f</sub>				42	84	
Gate Input Resistance	R <sub>g</sub>	f = 1	f = 1 MHz, open drain		0.78	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	_
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	53	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	0.9	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$ $dI/dt = 100 \text{ A/µs}, V_R = 25 \text{ V}$		-	160	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	1.2	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	14	-	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

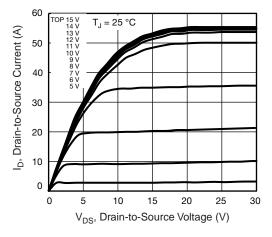


Fig. 1 - Typical Output Characteristics

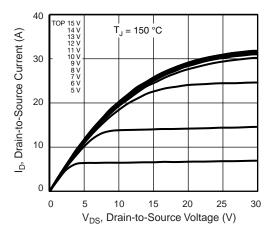


Fig. 2 - Typical Output Characteristics

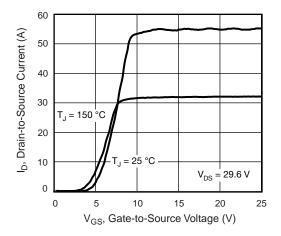


Fig. 3 - Typical Transfer Characteristics

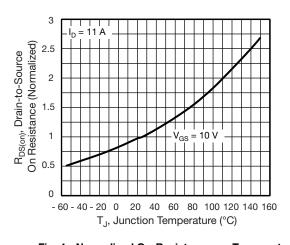


Fig. 4 - Normalized On-Resistance vs. Temperature

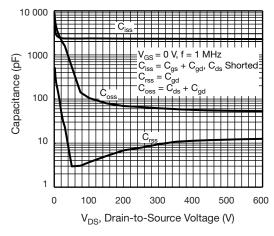


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

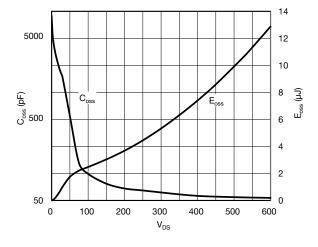


Fig. 6 -  $\mathrm{C}_{\mathrm{oss}}$  and  $\mathrm{E}_{\mathrm{oss}}$  vs.  $\mathrm{V}_{\mathrm{DS}}$ 

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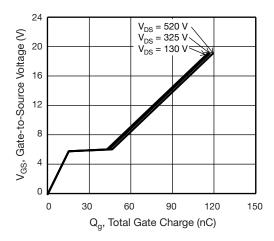


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

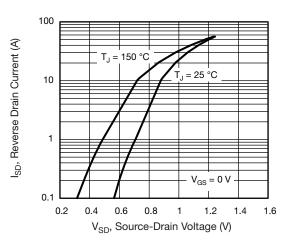


Fig. 8 - Typical Source-Drain Diode Forward Voltage

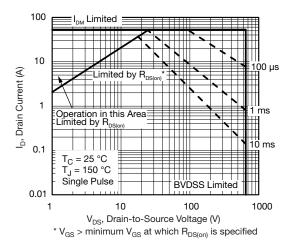


Fig. 9 - Maximum Safe Operating Area

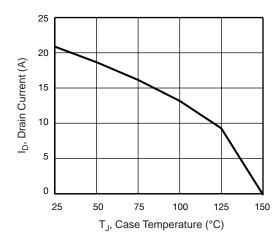


Fig. 10 - Maximum Drain Current vs. Case Temperature

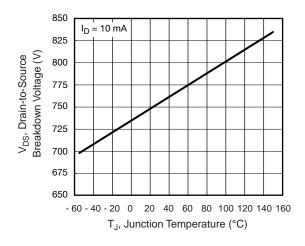


Fig. 11 - Temperature vs. Drain-to-Source Voltage



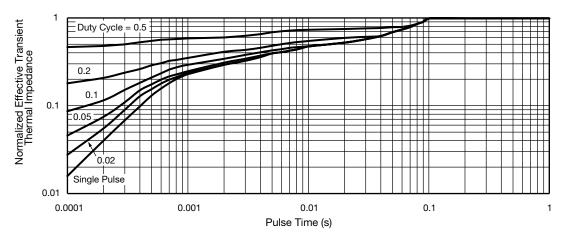


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

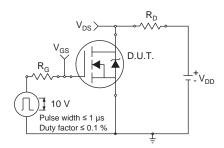


Fig. 13 - Switching Time Test Circuit

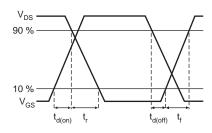


Fig. 14 - Switching Time Waveforms

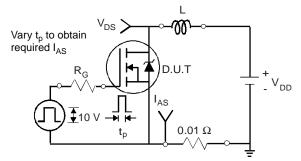


Fig. 15 - Unclamped Inductive Test Circuit

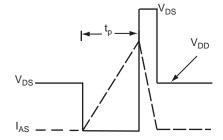


Fig. 16 - Unclamped Inductive Waveforms

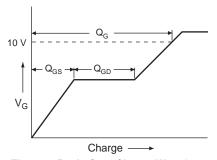


Fig. 17 - Basic Gate Charge Waveform

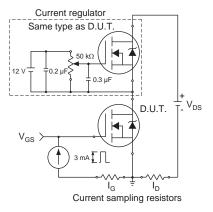
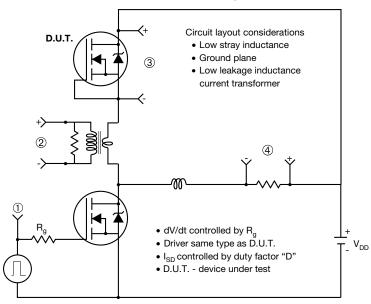


Fig. 18 - Gate Charge Test Circuit

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### Peak Diode Recovery dV/dt Test Circuit



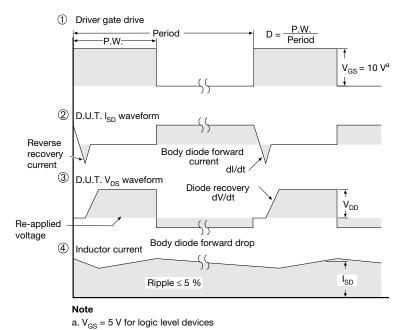
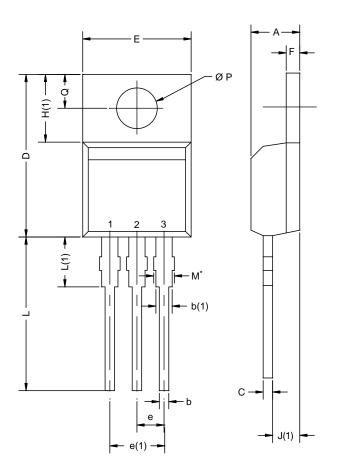


Fig. 19 - For N-Channel



### **TO-220AB**



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

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 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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